

<b>Notice of References Cited</b>	Application/Control No. 10/624,038	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner George C. Eckert II	Art Unit 2815	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,465,006	11-1995	Chen, Yaw-Hwang	257/557
	B	US-5,481,120	01-1996	Mochizuki et al.	257/49
	C	US-5,500,554	03-1996	Sato, Fumihiko	257/588
	D	US-5,506,427	04-1996	Imai, Kiyotaka	257/197
	E	US-5,903,018	05-1999	Shimawaki, Hidenori	257/198
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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